

# IBA in SIAM

**NFFA And Nanosafety** Workshop

Jorge Mejia & Julien Colaux  
January the 9<sup>th</sup>, 2020



*Synthesis  
Irradiation &  
Analysis of  
Materials*



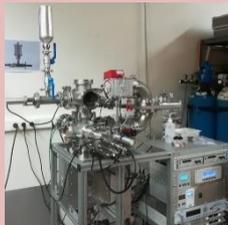
# SIAM Platform - unique facilities

## Plasma treatment

Thin films

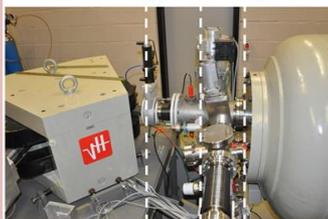


Powders



## Ion implantation (2MV Tandetron)

### Low energy implanter (2 – 35 keV)



Injector magnet (Horizontal scan)    Vertical scan    Sample    H.V.

### High energy implanter (100 keV – a few MeV)



Deflection plates (Horizontal and vertical scan)    Cold-finger    Beam delimitation    Sample

## Ion Beam Analysis



## XPS

K-alpha



Escalab 250Xi



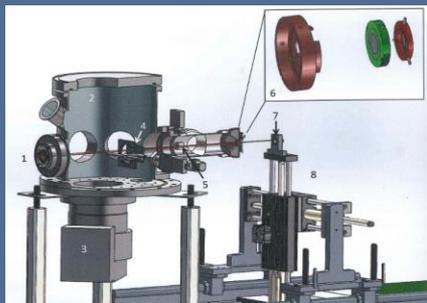
## ToF-SIMS



## Others

- Nanomaterials characterisation
- Tribology characterisation

## Cells irradiation (2MV Tandetron)



## Cells & small animals irradiation (X-ray irradiator; 225 kV)



## Equipment:

- 6 Plasma treatment installations
- 2MV Tandetron
- 2 XPS
- ToF-SIMS
- Tribology characterisation
- NPs characterisation
- X-ray irradiator
- ...



**Synthesis  
Irradiation &  
Analysis of  
Materials**

# What is Ion Beam Analysis?

Particle-Induced X-Ray Emission (PIXE)

Rutherford Backscattering Spectrometry (RBS)

Primary ion beam

Nuclear Reaction Analysis (NRA)

Particle-Induced Gamma-Ray Emission (PIGE)

Elastic Recoil Detection (ERD)

Accelerator of particles

Sample

**Quantitative** (sensitivity  $\sim 10$  wt.ppm)

**Non-destructive**

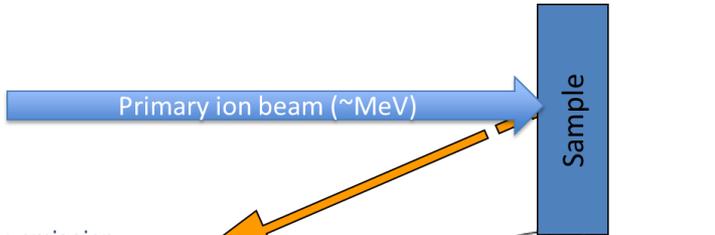
**Model-free**

**Depth profiling** (depth resolution  $\sim 1-10$  nm)

**2D elemental maps** (lateral resolution  $\sim 1$   $\mu\text{m}$ )

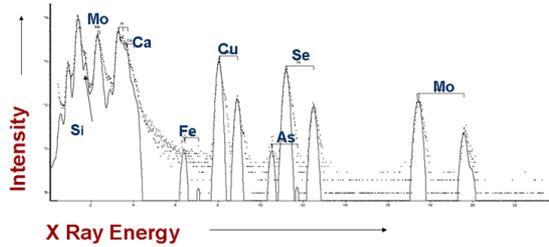
**H depth profiling capability**

# Ion Beam Analysis - Particle-Induced X-Ray Emission (PIXE)

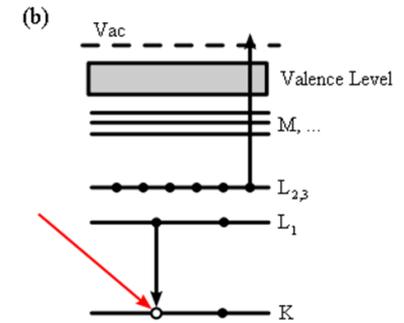
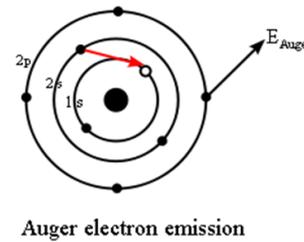
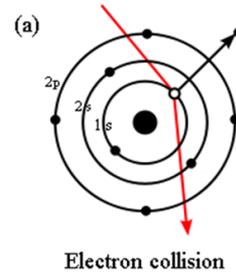


## PIXE

Characteristic X-ray emission.  
 Simultaneous Na to U detection.  
 Sensitivity: ppm



Detector  
 Si(Li) or  
 LEGE or  
 SDD



- electron in, electron out = **Auger**
- electron in, photon out = **SEM-EDX**
- photon in, electron out = **XPS**
- ion in, photon out = **PIXE**

Taken from the Wikipedia article on Auger Electron Spectroscopy 18Feb09  
 Auger\_Process.svg from Wikipedia Commons.

# Application fields for PIXE

Materials science

Quantitation of CNTs catalysts  
Photovoltaics  
Airborne particulate matter (APM)

Life science

Bio-distribution and bio-persistence of ENMs  
Protein structure

Forensics

INNOVATION

## Authentification de bouteilles de vin anciennes par faisceaux

X-RAY  
SPECTROMETRY



[Explore this journal >](#)

Research Article

### Trace element profiling of gunshot residues by PIXE and SEM-EDS: a feasibility study

M. J. Bailey  K. J. Kirkby, C. Jeynes

First published: 20 February 2009 [Full publication history](#)

DOI: 10.1002/xrs.1142 [View/save citation](#)

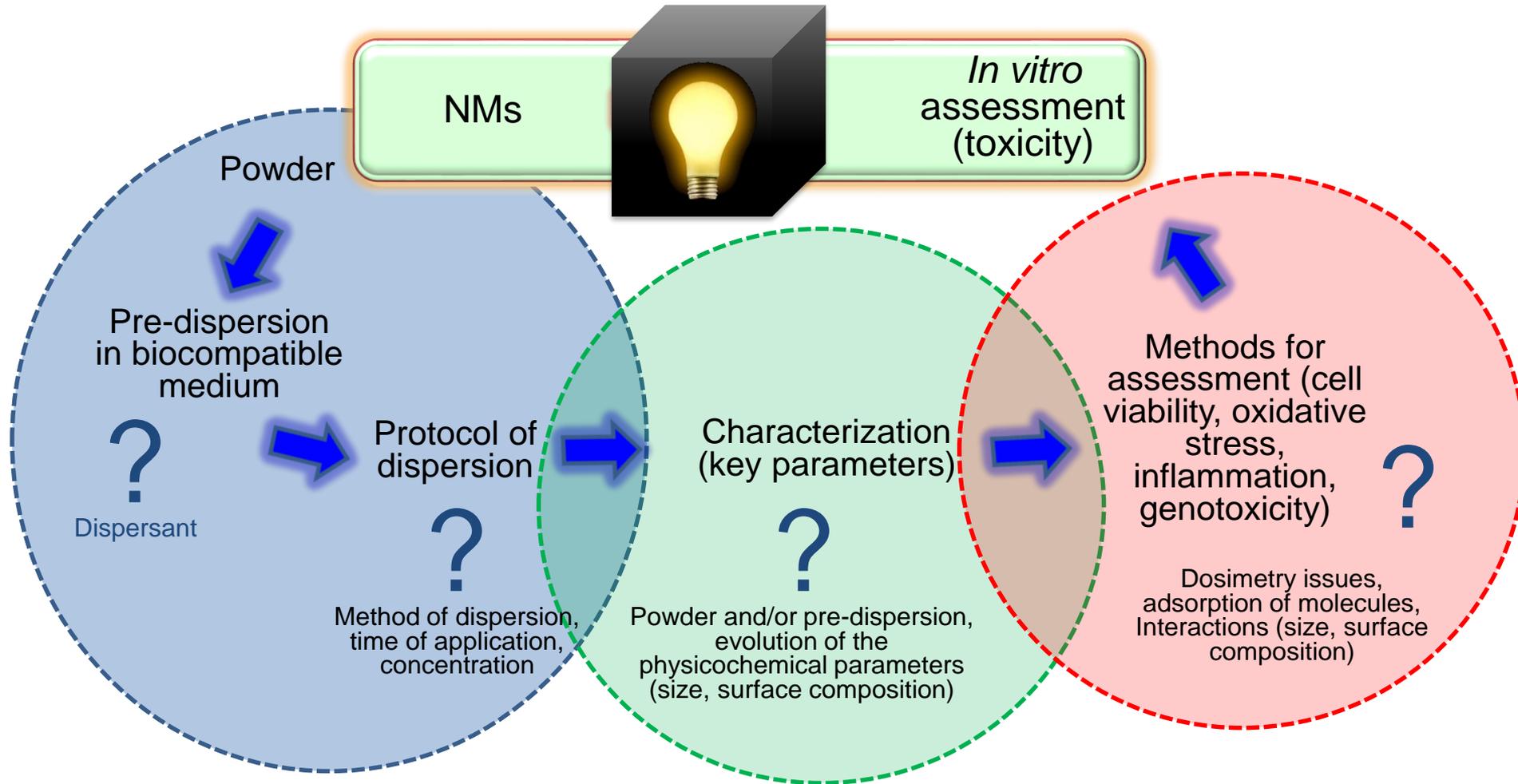
Cited by (CrossRef): 15 articles [Check for updates](#) | [Citation tools](#) ▼



#### Abstract

A feasibility study was carried out into the use of particle-induced x-ray emission (PIXE) on the ion microprobe for the characterisation of gunshot residues (GSR). We compare these results with the conventional technique, scanning electron microscopy with energy dispersive x-ray spectroscopy (SEM-EDS). Samples of gunshot residue from four different sources were collected. Individual particles of GSR were analysed by SEM-EDS using a 30-keV electron beam focussed to ~10 nm, and PIXE using a 2.5-MeV proton beam focussed to ~4 µm. PIXE revealed trace or minor elements undetectable by SEM-EDS, thereby strengthening the discrimination between different types of GSR. Copyright © 2009 John Wiley & Sons, Ltd.

# Assessing the possible hazard associated to NPs



# Nanosafety related characterization

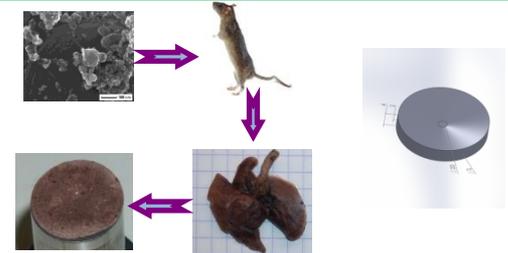
## Quantitative analysis of NPs in complex systems

### Characterisation of NMs

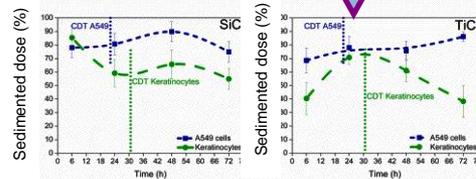
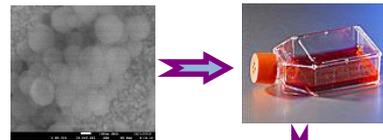
CLS, XPS, SEM, TEM, Turbiscan, PIXE, BET, XRD



### Biodistribution and biopersistence (*in vivo*) of NMs (Biopersistence of NPs in rat organs)

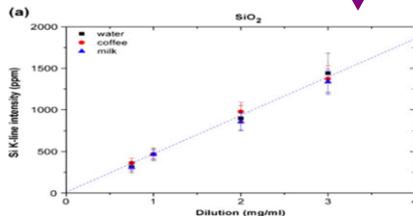
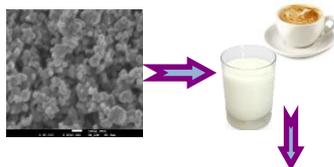


### *in vitro* safety assessment

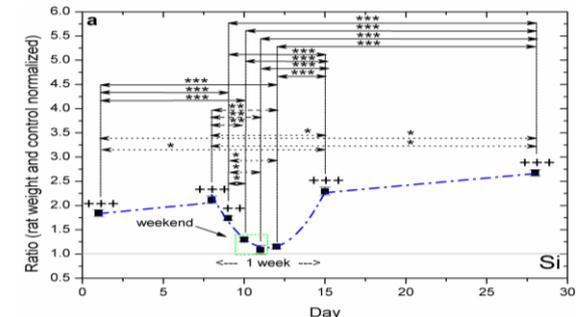
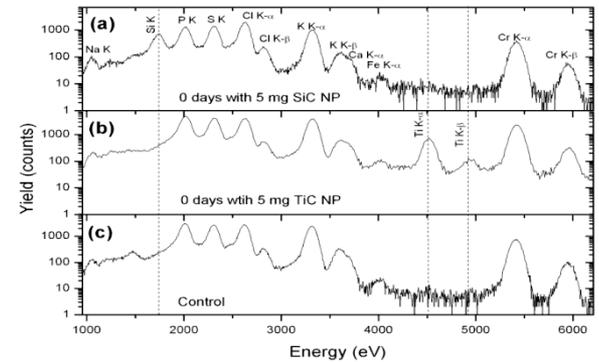


Mejia et al, Journal of Nanoparticle Research (2013) 15, 8, 1875

### Quantification of NMs in complex media (i.e. Quantification of SiO<sub>2</sub> NPs in water, coffee and milk)



Lozano, Mejia et al, Analytical and Bioanalytical Chemistry. 403, 10, 2835-41.



Lozano et al, Toxicology and Applied Pharmacology 264 (2012) 232-245

# NPs fate in paints

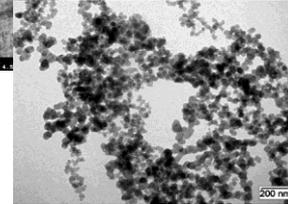
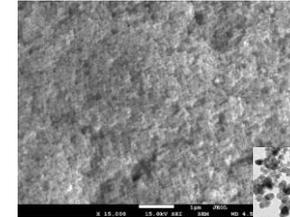
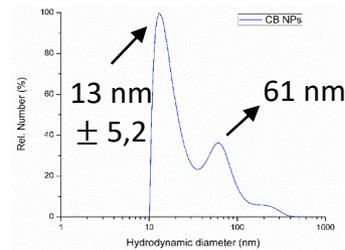


## Whole-body exposure chamber

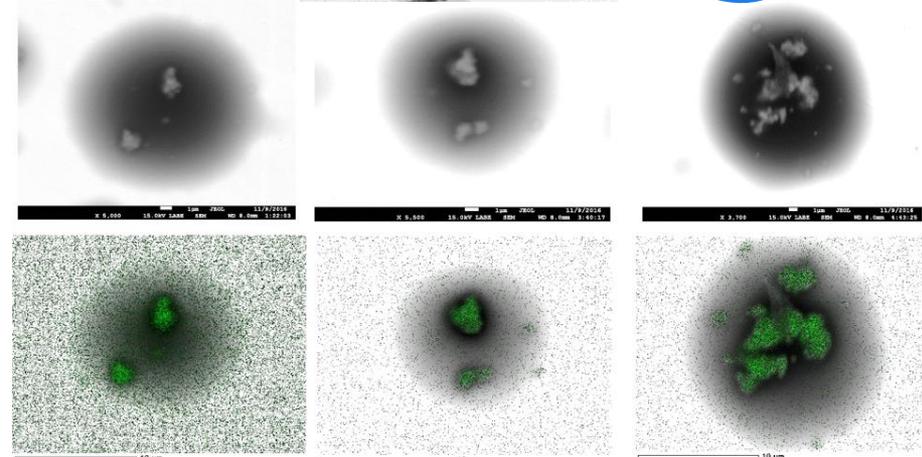
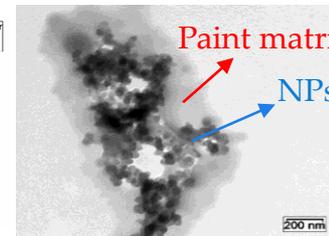
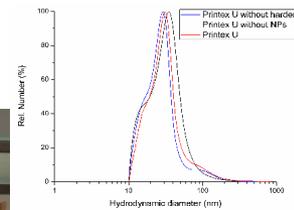


Inhalation model designed for in-vivo experiments on mice. The system is composed of a mixing chamber, an animal cage and ELPI instrument.

### CB NPs in H<sub>2</sub>O



### CB NPs in paint (Dilution 20×)



Overlay of SEM images and Ti mapping (recorded with 100 scans) at 3 different locations in the paint overspray sample. Sample was analyzed with a JEOL 7500 F operating at 50 keV, 20  $\mu$ A and with LABE detector (backscattered electrons are detected)

# Focused incident beam ( $\mu$ -PIXE)

## Micrometeoroid impacts on the HUBBLE space telescope Wide Field and Planetary Camera 2 (WFPC2)

Experiments performed at the University of Surrey (UK)

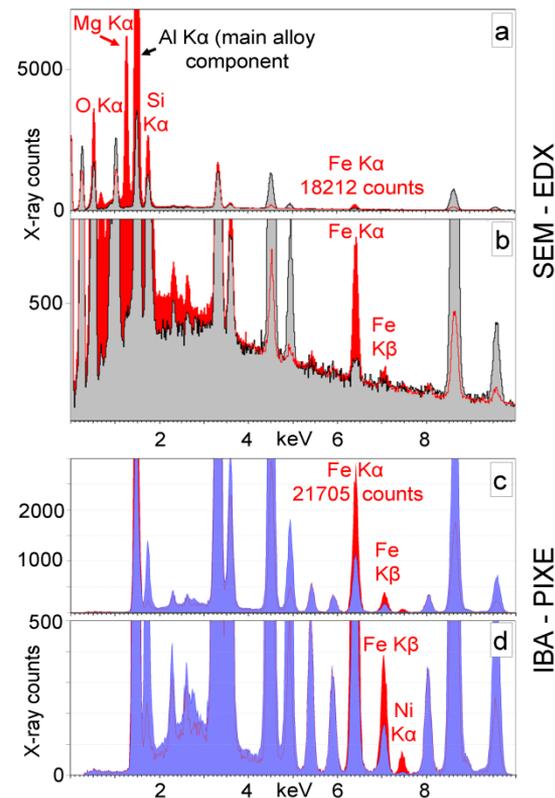
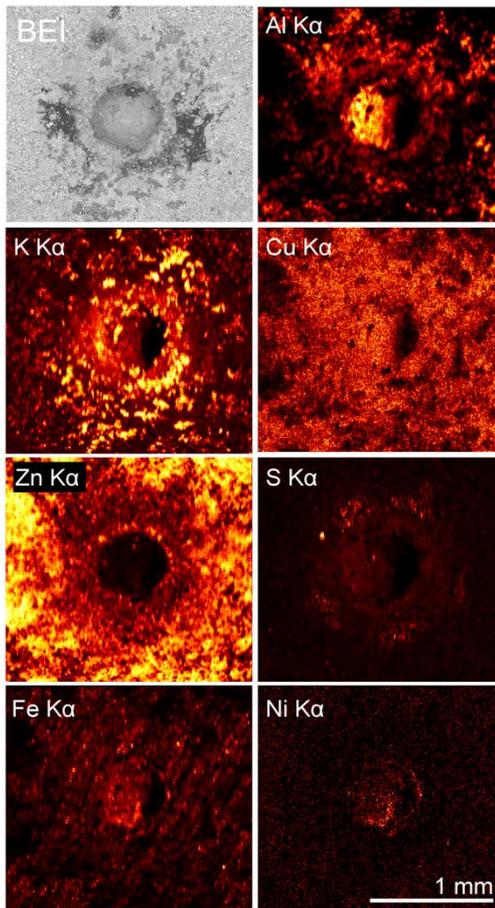
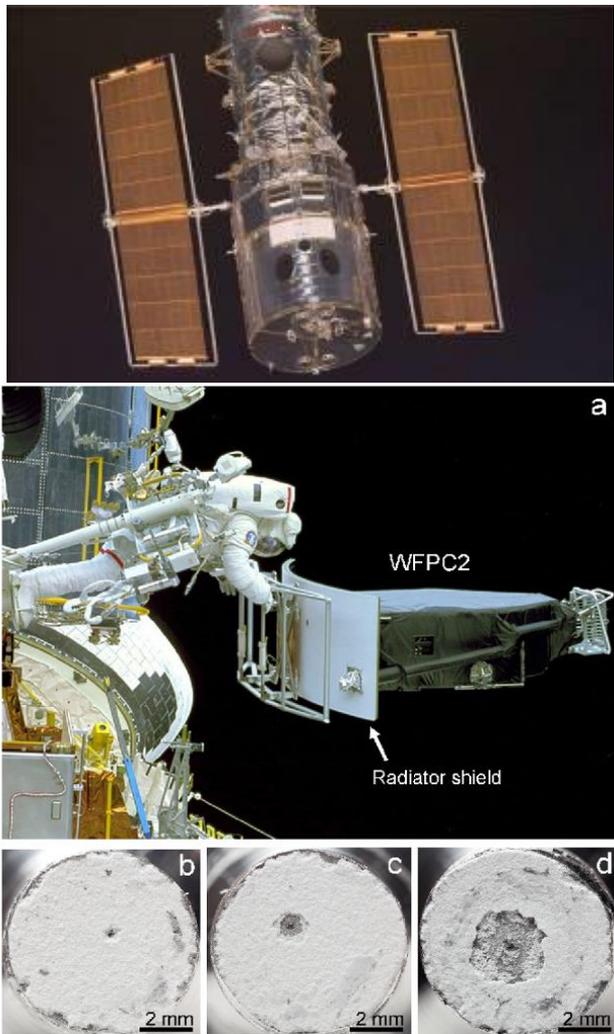


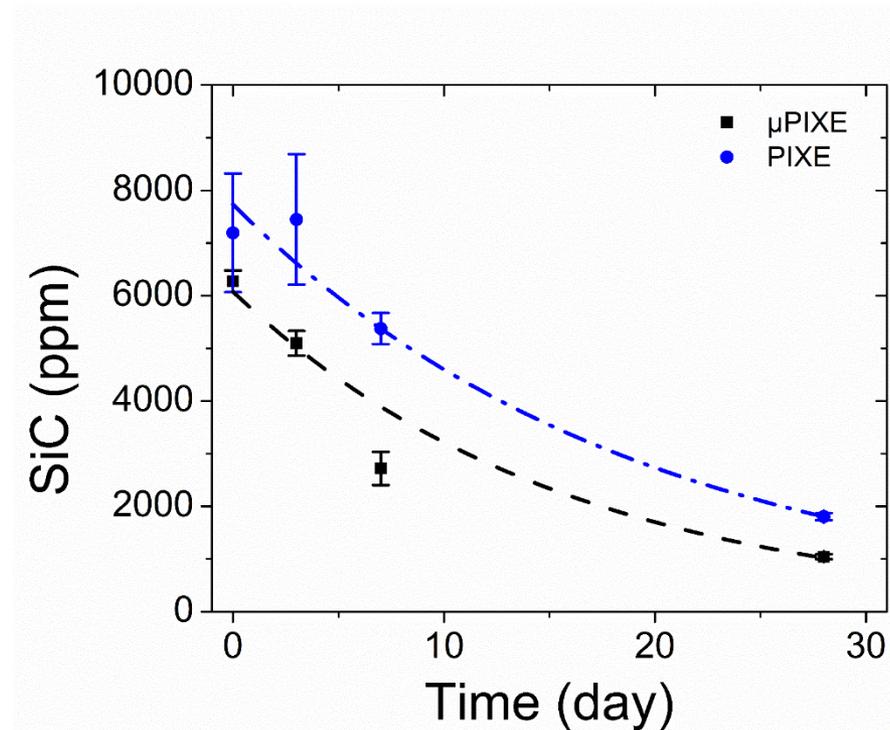
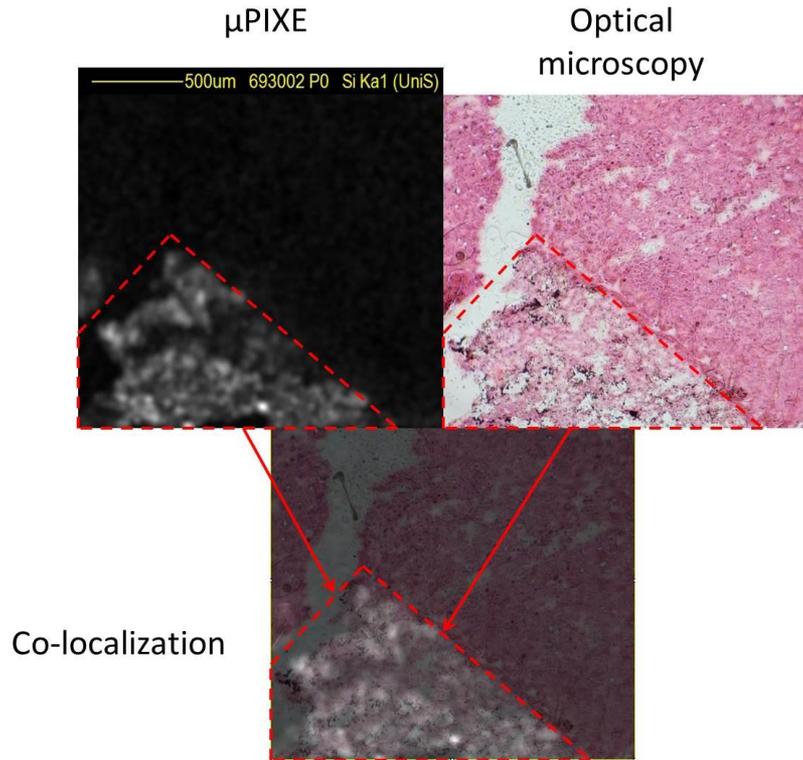
Fig. 2. WFPC2-462: BEI and PIXE maps across centre of feature.

WFPC2-462: a) and b) SEM-EDX of metal in pit (red) and surrounding metal (grey), normalized to background between Cr K $\alpha$  and Cr K $\beta$ ; c) and d) PIXE of metal area inside pit (red) and surrounding metal (blue), normalized to Cr K $\alpha$  peak area.

$\mu$ -Probe now available @ UNamur

# Focused incident beam ( $\mu$ -PIXE)

## Analysis of rat lungs



O. Lozano, J.L. Colaunx et al.,

*“Fast, asymmetric and non-homogeneous clearance of SiC nano-aerosol after 5 day exposure using ion beam analysis”*  
**accepted in Nanomedicine (2017)**

# Know how

- Nanomaterials (NMs) and nanoparticles (NPs) physicochemical characterisation (pristine forms, dispersions, complex matrices, environmental compartments, ...)
- Fate and biodistribution studies at cellular and/or organ levels.
- Multielemental determination in complex matrices
- FATE OF NMs: Evolution of NMs (surface) in specific compartments. Released (nano)materials (intentional or unintentional, during manufacturing, after erosion or aging).
- Detection and evaluation of released (nano)materials
- IN SILICO MODELLING (sedimentation of NMs in aqueous media, environmental compartments).



(2011-2015) Joint Research Activities, networking activities and provision of Transnational Access functions.



(2011-2015) Development of SOPs for NPs characterization.



(2013-2016) Development and testing of SOPs for characterization and quantification of NMs.



(2015-2018) Characterization of the aerosol (paint with NPs) in real exposure conditions.

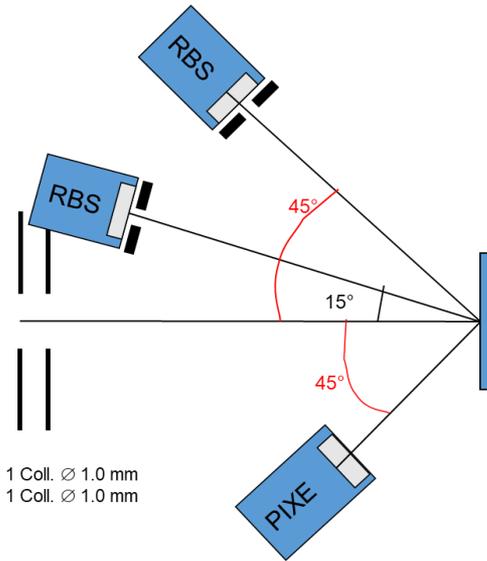


(2018-2021) Characterization and dosimetry of NMs in vitro and environmental samples. In silico modelling.

# Liquid sample analysis Zebrafish eggs samples (LU)

Exposure to TiO<sub>2</sub> NPs (NM-105) in ecotox media (M7, egg water)

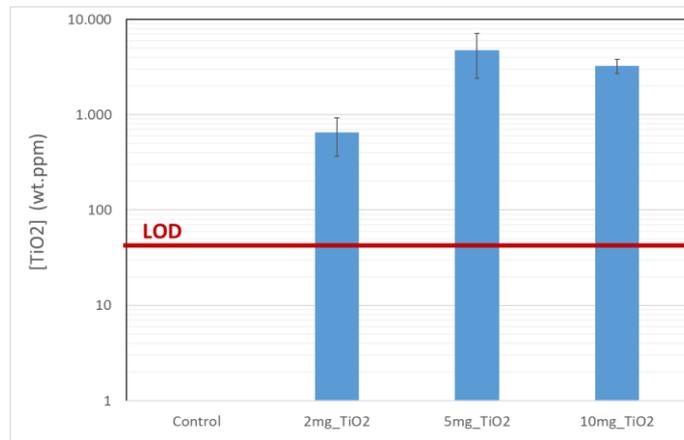
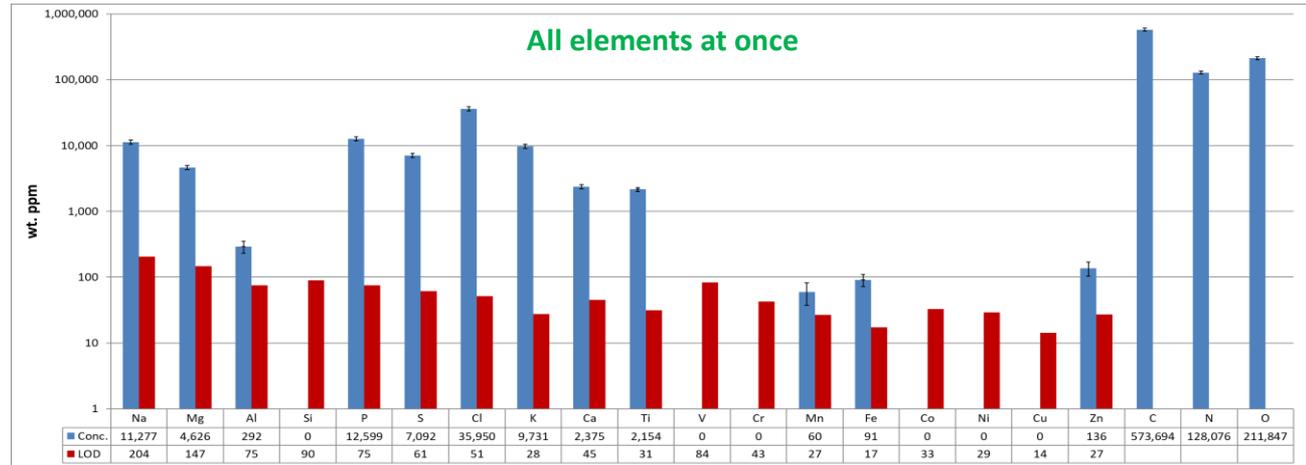
Experimental setup (2,5 MeV)



1 Coll. ∅ 1.0 mm  
1 Coll. ∅ 1.0 mm

Solid samples!

=> "pellets"



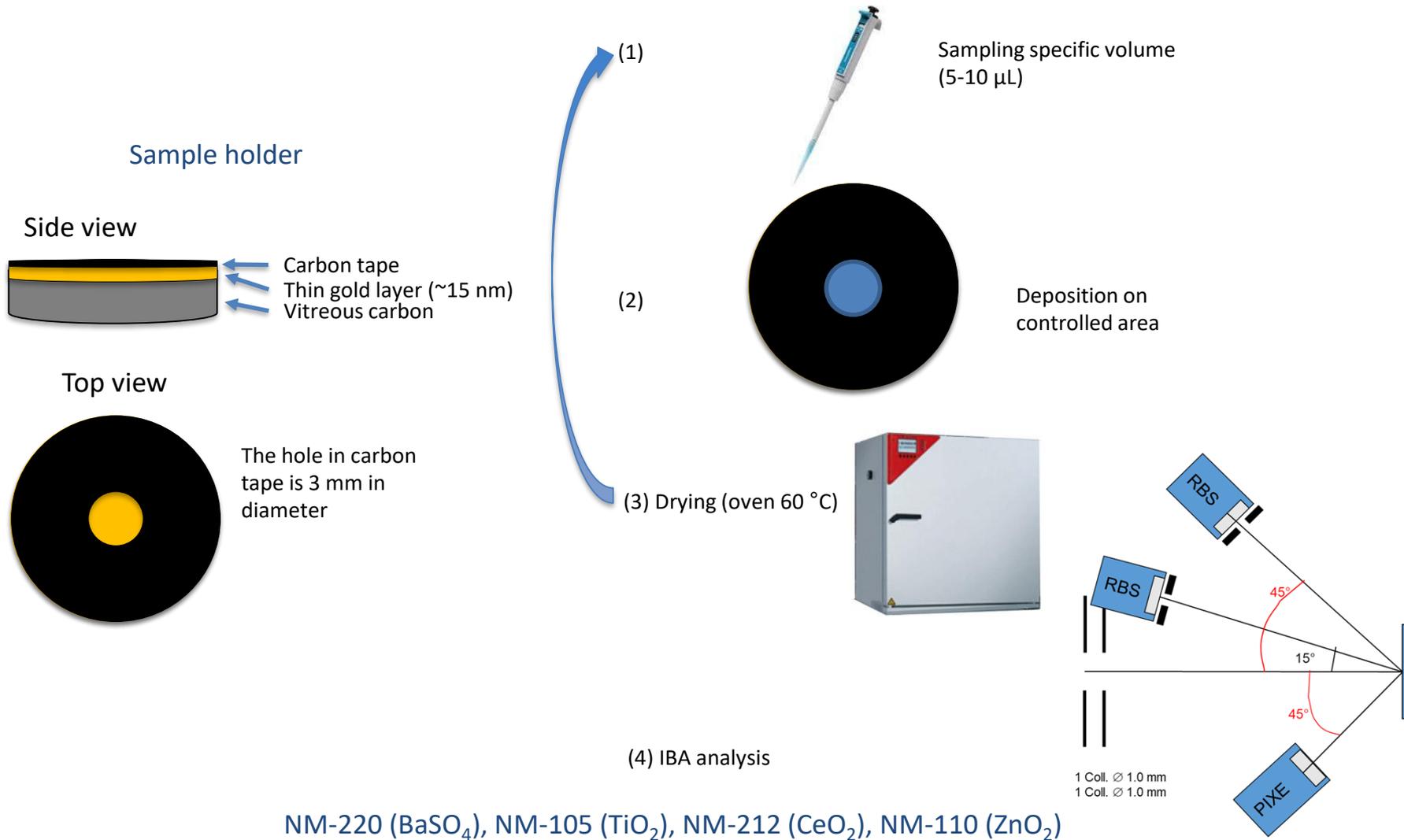
LOD = 40 wt.ppm

=> Must be improved for ecotox samples

➔ Potential for simulation  
(data with low uncertainty).

Translocation experiments (apical, basal, membrane, cells).

# Liquid sample and configuration settings

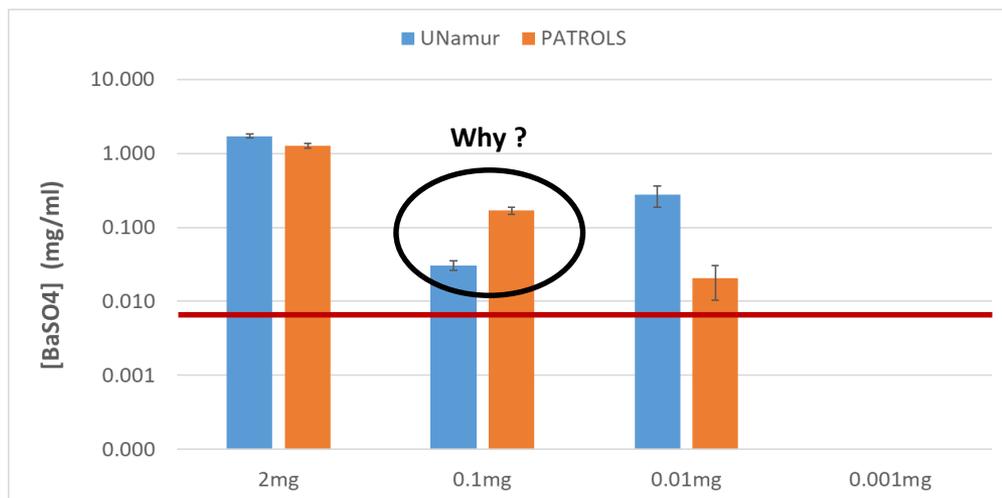


# Liquid sample results (AMI)

	sample	[Ba] wt.ppm	Unc. Wt.ppm	LOD wt.ppm
UNamur	2mg_BaSO4	612,219	39,251	1,227
UNamur	0.1mg_BaSO4	11,301	1,639	2,861
UNamur	0.01mg_BaSO4	296,200	94,441	2,659
UNamur	0.001mg_BaSO4			1,664
PATROLS	2mg_BaSO4	561,051	36,446	2,042
PATROLS	0.1mg_BaSO4	29,721	3,118	2,541
PATROLS	0.01mg_BaSO4	4,672	2,317	2,733
PATROLS	0.001mg_BaSO4			2,691

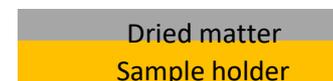


	sample	[BaSO4] mg/ml	Unc. mg/ml	LOD mg/ml
UNamur	2mg	1.708	0.1095	0.003
UNamur	0.1mg	0.031	0.0045	0.004
UNamur	0.01mg	0.277	0.0882	0.001
UNamur	0.001mg			0.002
PATROLS	2mg	1.266	0.0822	0.005
PATROLS	0.1mg	0.169	0.0178	0.014
PATROLS	0.01mg	0.021	0.0102	0.012
PATROLS	0.001mg			0.012



Uncertainty values are established from a bottom-up approach (uncertainty budget).

Ideally we should get this:

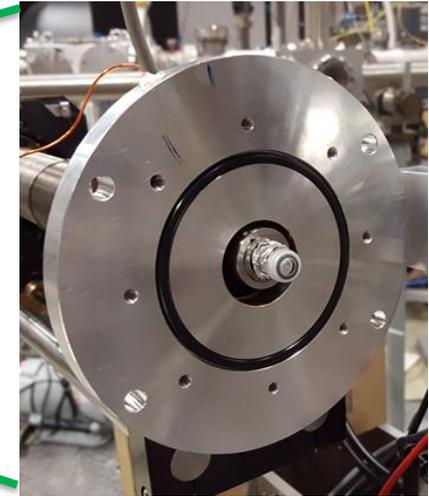
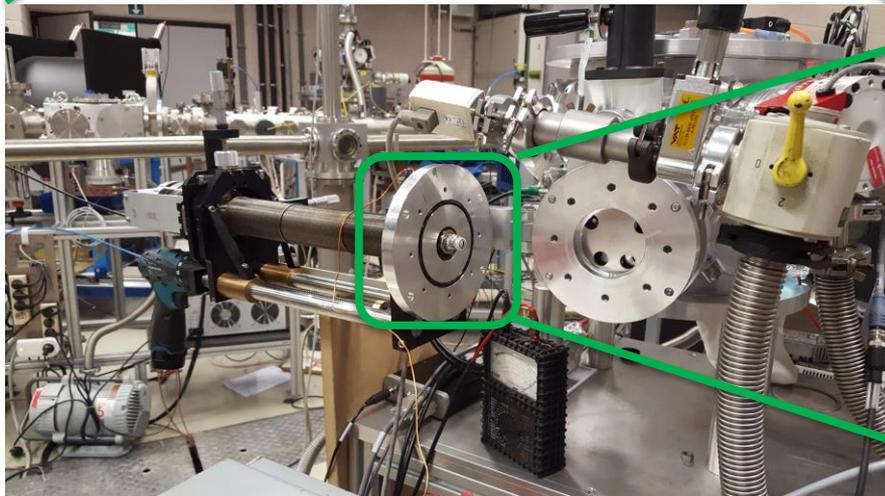
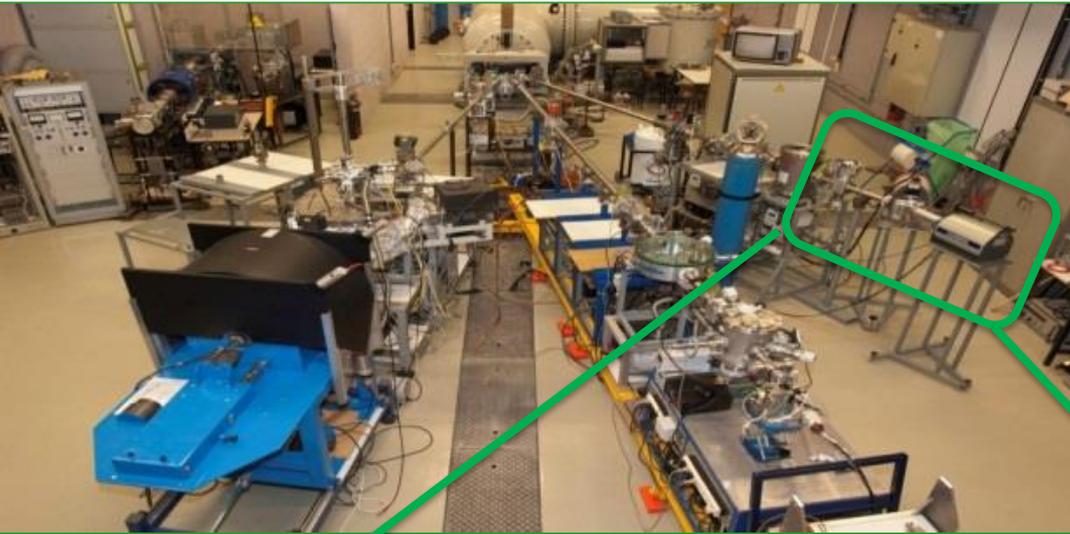


However:



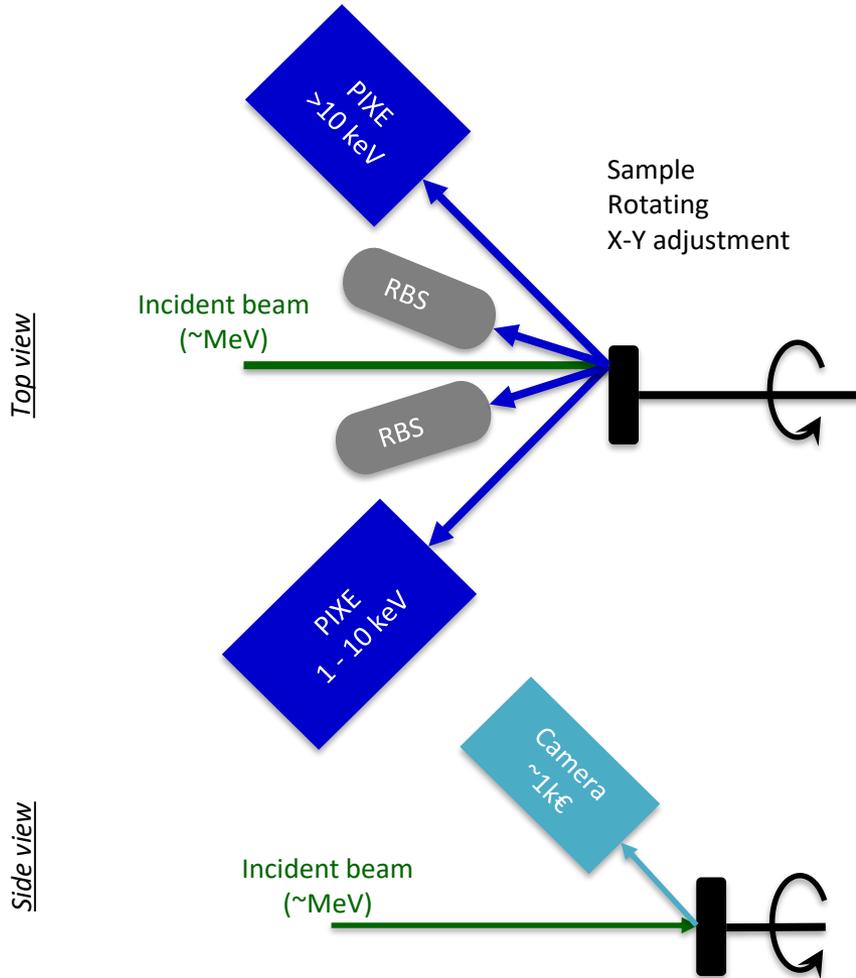
Moreover, LOD still too high!

# Measurement of liquid sample by IBA



# Measurement of liquid sample by IBA

**Improving LOD**  
(set-up under development)

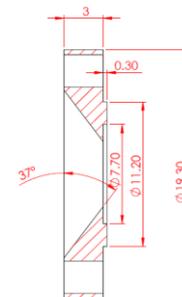
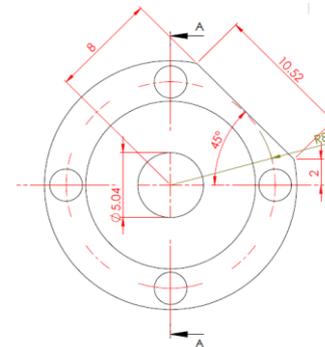


**Improving sample uniformity**

Cells for liquid sample (50  $\mu$ L)



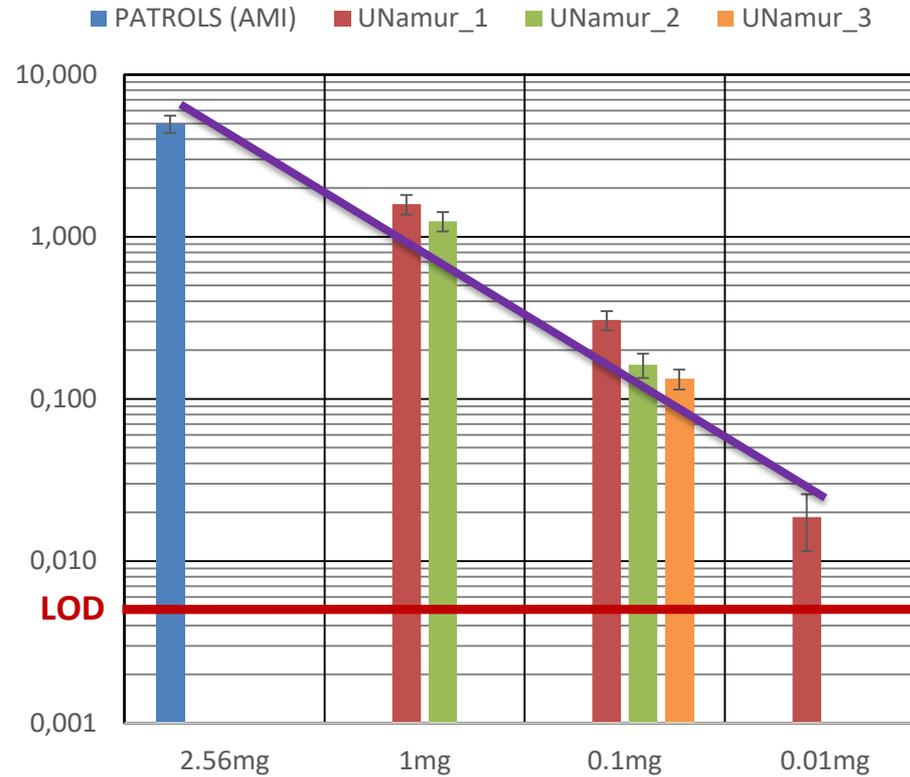
- ← Screws
- ← Stainless steel
- ← Aluminized Mylar (0,05  $\mu$ m)



SECTION A-A

# Some last results

NM-105 (TiO<sub>2</sub>)



Values given are indicative or typical “best” values.

Different applications may have widely differing performances.

Possible primary beam energies and types are indicated. A wide variety may be used.

	SIMS	XTEM	SAM	GD-OES	XPS	LA - ICP-MS	IBA
<b>Primary beam</b>	keV ions	~100 keV electrons	~100 keV electrons	plasma	X-rays	Pulsed laser	~3 MeV light ions ~30 MeV heavy ions
<b>Detected signal</b>	Sputtered ions	Primary electrons in phase contrast	Auger electrons	visible photons	Photo-electrons	Evaporated ions	X-rays; Nuclear reaction products: scattered primaries, target recoils and $\gamma$ -rays
<b>Destructive</b>	Yes	Yes	Yes	Yes	Yes	Yes	No
<b>Depth resolution</b>	2 nm	0.1 nm	2 nm	20 nm	2 nm	10 nm	2 nm
<b>Information depth</b>	500 nm	100 nm	500 nm	50 $\mu$ m	500 nm	--	15 $\mu$ m
<b>Lateral resolution</b>	50 nm	0.1 nm	2 nm	1 mm	3 $\mu$ m	10 mm	500 nm
<b>Elemental Imaging</b>	Yes	EELS, EDX	Yes	No	Yes	No	Yes
<b>Ambient analysis</b>	No	No	No	No	No	Yes	Yes
<b>Sample preparation</b>	No	Yes	UHV	No	UHV	No	No
<b>Quantitative</b>	?	No	Yes	Yes	Yes	Yes	Yes
<b>Standards needed</b>	Yes	--	Yes	Yes	Yes	Yes	No
<b>Elemental sensitivity</b>	$10^{-8}$	$10^{-1}$	$10^{-3}$	$10^{-6}$	$10^{-3}$	$10^{-9}$	$10^{-6}$
<b>Accuracy</b>	--	--	10%	10%	5%	5%	1%
<b>Traceability</b>	--	--	--	--	Yes	Yes	primary

C. Jaynes & J.L. Colaux, *"Thin film depth profiling by ion beam analysis"*, [Analyst 141 \(2016\), 5944-5985](#).

# Progress so far

- Liquid samples measurements: minimal manipulation and small volumes (~50 µL).
- Geometry OK (improvements are still possible, LOD still to be reduced?)
- Actual LOD is about 0,05 mg/mL, “sample concentration” is required for lower concentrations.
- Sets of data produced per sample (NMs and matrix information in the same run).
- Cross check/validation on the NMs dispersion protocol (exposure concentrations).
- Low uncertainty values and valuable data for simulation purposes.
- High potentiality for analyses of complex samples (in vitro/in vivo/ecotox, ...)

## On going

- Sample stability study programmed.
- Improving sample preparation for solid samples.

## Technological Platform



Thank you for your attention



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**“Your potential partner for  
surface, materials and  
nanomaterials characterization”**